



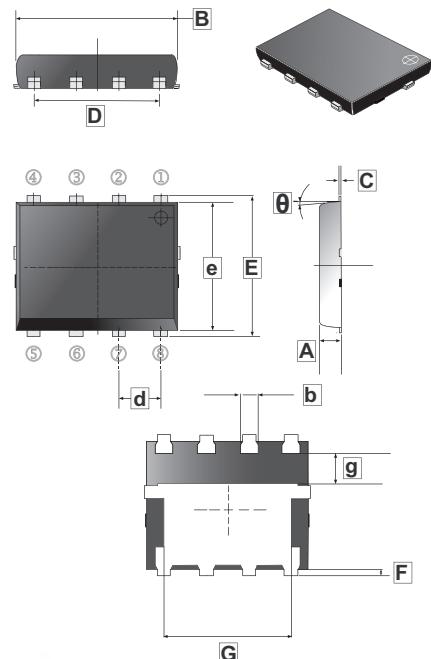
**YEA SHIN TECHNOLOGY CO., LTD**

**YS5465BA**

## P-Channel Enhancement MOSFET VDS = -60V, ID = -16A



**PPAK5x6**



### DESCRIPTION

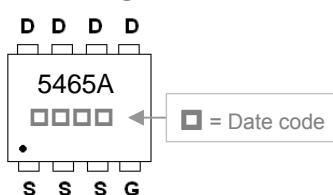
The YS5465BA is the highest performance P-ch MOSFETs with super high dense cell design for extremely low  $R_{DS(ON)}$  and gate charge for most of the synchronous buck converter applications.

The YS5465BA meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

### FEATURES

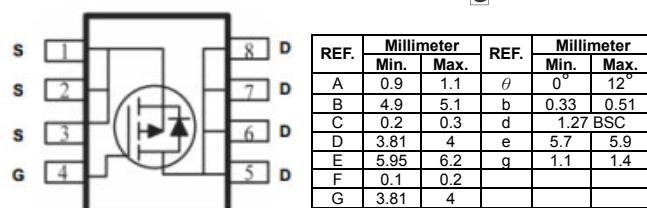
- Low Reverse Transfer Capacitance
- Improved dv/dt Capability
- Green Device Available
- High Switching Speed
- 100% EAS Guaranteed

### MARKING



### PACKAGE INFORMATION

Package	MPQ	Leader Size
PPAK5x6	3K	13 inch



### Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	-60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>1</sup>	$I_D @ T_C=25^\circ\text{C}$	-16	A
	$I_D @ T_C=100^\circ\text{C}$	-10	A
Pulsed Drain Current <sup>2</sup>	$I_{DM}$	-64	A
Continuous Drain Current <sup>1</sup>	$I_D @ T_A=25^\circ\text{C}$	-5	A
	$I_D @ T_A=70^\circ\text{C}$	-4	A
Total Power Dissipation <sup>4</sup>	$P_D @ T_C=25^\circ\text{C}$	25	W
	$P_D @ T_A=25^\circ\text{C}$	2	W
Single Pulse Avalanche Energy, $L=0.1\text{mH}^3$	$E_{AS}$	51	mJ
Single Pulse Avalanche Current, $L=0.1\text{mH}^3$	$I_{AS}$	-32	A
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 ~ +150	°C

### Thermal Data

Parameter	Symbol	Conditions	Max. Value	Unit
Thermal Resistance Junction-ambient <sup>1</sup>	$R_{\theta JA}$	Steady State	62.5	°C/W
Thermal Resistance Junction-case <sup>1</sup>	$R_{\theta JC}$	Steady State	5	°C/W

# DEVICE CHARACTERISTICS

## YS5465BA

### Electrical Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	-60	-	-	V	$\text{V}_{\text{GS}}=0, \text{I}_D=-250\mu\text{A}$
Gate Threshold Voltage	$\text{V}_{\text{GS}(\text{th})}$	-1.0	-1.7	-2.5	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=-250\mu\text{A}$
Gate-Source Leakage Current	$\text{I}_{\text{GSS}}$	-	-	$\pm 100$	nA	$\text{V}_{\text{GS}}= \pm 20\text{V}$
Drain-Source Leakage Current	$\text{I}_{\text{DSS}}$	-	-	-1	$\mu\text{A}$	$\text{V}_{\text{DS}}=-60\text{V}, \text{V}_{\text{GS}}=0$
Static Drain-Source On-Resistance <sup>2</sup>	$\text{R}_{\text{DS}(\text{ON})}$	-	44	48	$\text{m}\Omega$	$\text{V}_{\text{GS}}=-10\text{V}, \text{I}_D=-8\text{A}$
		-	55	65		$\text{V}_{\text{GS}}=-4.5\text{V}, \text{I}_D=-4\text{A}$
Total Gate Charge <sup>2</sup>	$\text{Q}_g$	-	22	-	$\text{nC}$	$\text{I}_D=-8\text{A}$ $\text{V}_{\text{DS}}=-30\text{V}$ $\text{V}_{\text{GS}}=-10\text{V}$
Gate-Source Charge	$\text{Q}_{\text{gs}}$	-	4.1	-		
Gate-Drain ("Miller") Change	$\text{Q}_{\text{gd}}$	-	5.2	-		
Turn-on Delay Time <sup>2</sup>	$\text{T}_{\text{d}(\text{on})}$	-	13	-	$\text{ns}$	$\text{V}_{\text{DS}}=-30\text{V}$ $\text{I}_D=-1\text{A}$ $\text{V}_{\text{GS}}=-10\text{V}$ $\text{R}_G=6\Omega$
Rise Time	$\text{T}_r$	-	42	-		
Turn-off Delay Time	$\text{T}_{\text{d}(\text{off})}$	-	65	-		
Fall Time	$\text{T}_f$	-	16	-		
Input Capacitance	$\text{C}_{\text{iss}}$	-	1256	-	$\text{pF}$	$\text{V}_{\text{GS}}=0\text{V}$ $\text{V}_{\text{DS}}=-30\text{V}$ $f=1.0\text{MHz}$
Output Capacitance	$\text{C}_{\text{oss}}$	-	87	-		
Reverse Transfer Capacitance	$\text{C}_{\text{rss}}$	-	59	-		

### Guaranteed Avalanche Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Single Pulse Avalanche Energy <sup>5</sup>	EAS	3.2	-	-	$\text{mJ}$	$\text{V}_{\text{DD}}=-25\text{V}, \text{L}=0.1\text{mH}, \text{I}_{\text{AS}}=-8\text{A}$

### Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Diode Forward Voltage <sup>2</sup>	$\text{V}_{\text{SD}}$	-	-0.72	-1.0	V	$\text{I}_S=-1\text{A}, \text{V}_{\text{GS}}=0\text{V}, \text{T}_J=25^\circ\text{C}$
Continuous Source Current <sup>1,6</sup>	$\text{I}_S$	-	-	-16	A	---

Notes: 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

2. The data tested by pulsed, pulse width  $\leq 300\text{us}$ , duty cycle  $\leq 2\%$ .
3. The EAS data shows Max. rating. The test condition is  $\text{V}_{\text{DD}}=-25\text{V}, \text{V}_{\text{GS}}=-10\text{V}, \text{L}=0.1\text{mH}, \text{I}_{\text{AS}}=-32\text{A}$ .
4. The power dissipation is limited by  $150^\circ\text{C}$  junction temperature.
5. The Min. value is 100% EAS tested guarantee.
6. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.

# DEVICE CHARACTERISTICS

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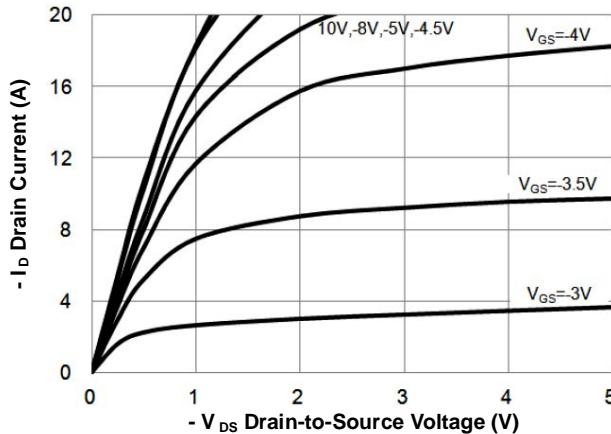


Fig.1 Typical Output Characteristics

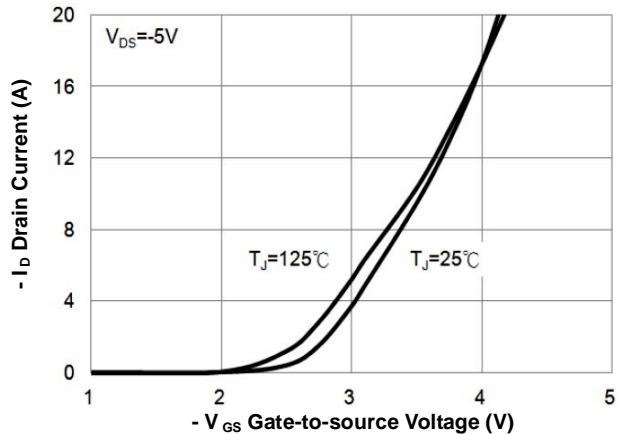


Fig.2 Transfer Characteristics

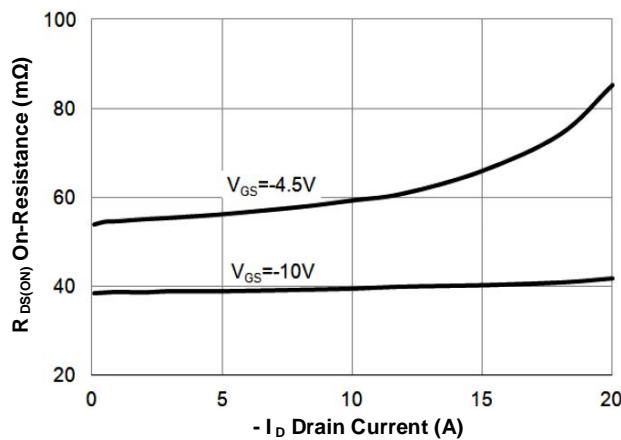


Fig.3 On-Resistance vs. Drain Current

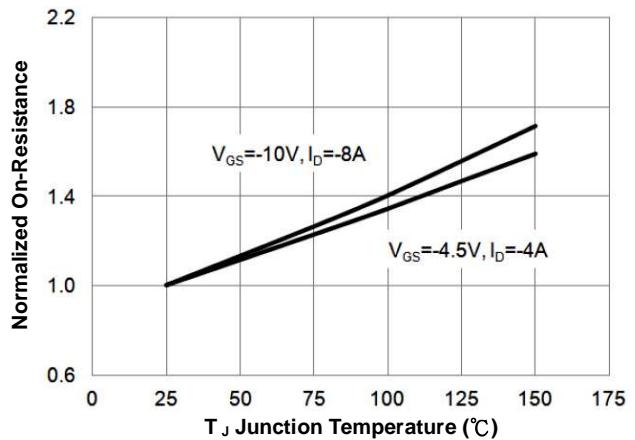


Fig.4 Normalized  $R_{DS(ON)}$  vs.  $T_J$

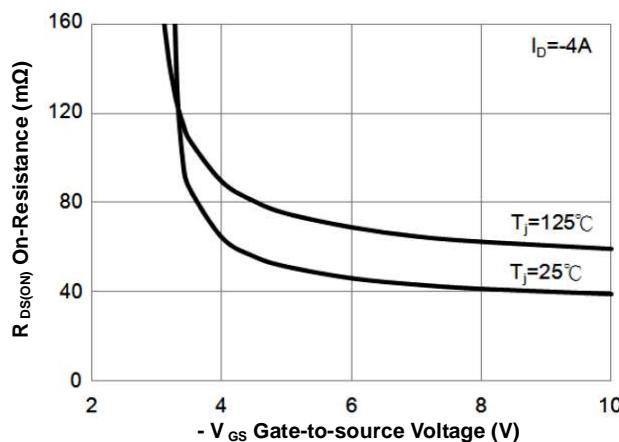


Fig.5 On-Resistance vs. G-S Voltage

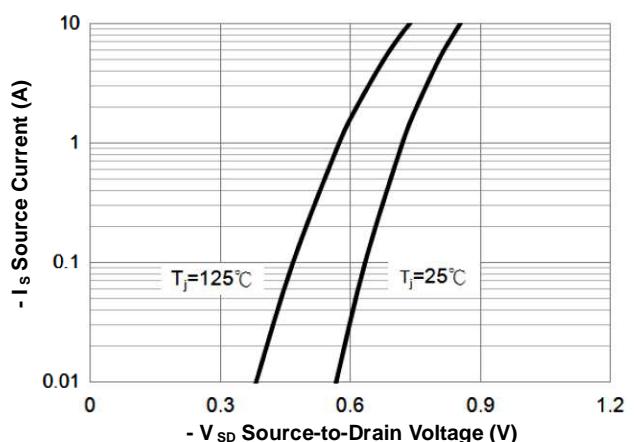


Fig.6 Forward Characteristics of Reverse

# DEVICE CHARACTERISTICS

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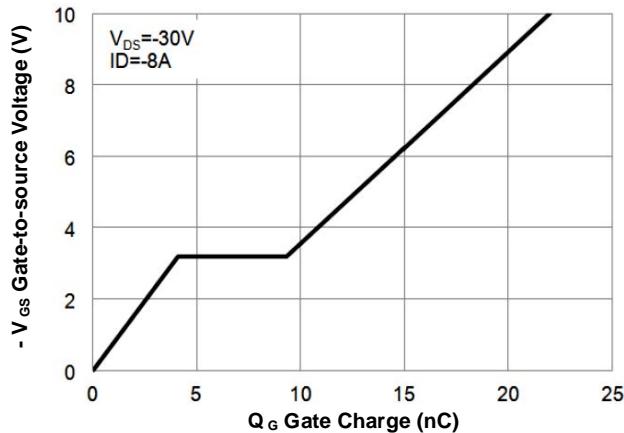


Fig.7 Gate Charge Characteristics

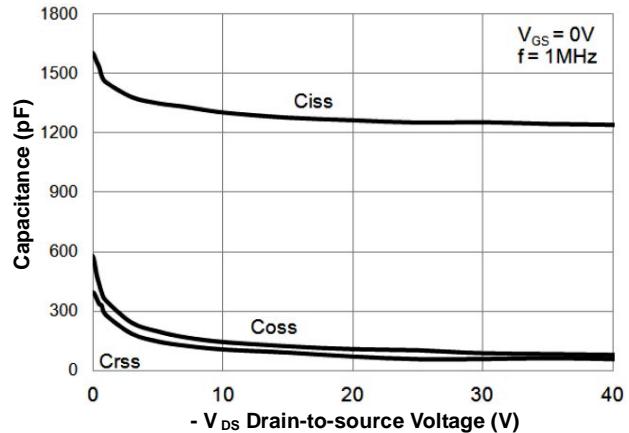


Fig.8 Capacitance Characteristics

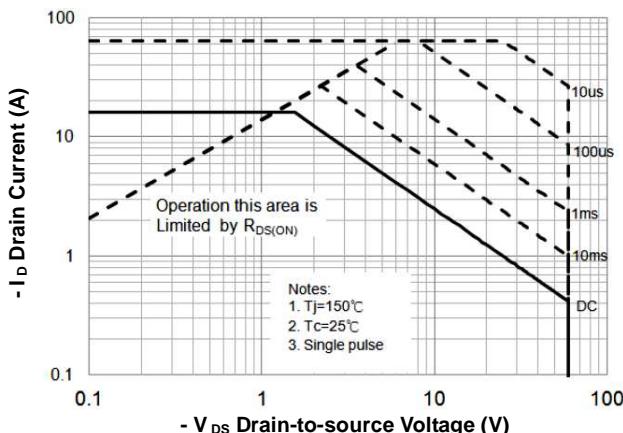


Fig.9 Safe Operating Area

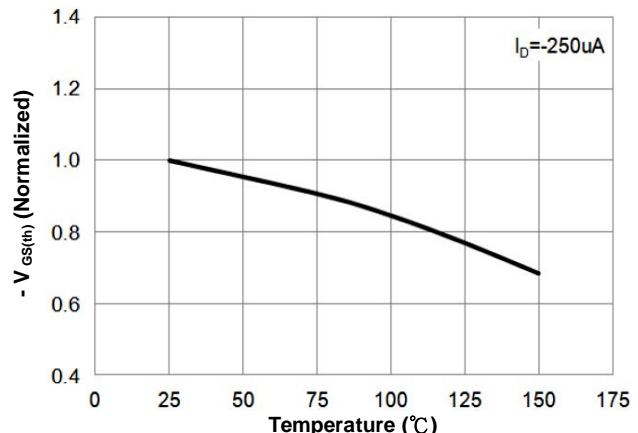


Fig.10 Normalized  $V_{GS(th)}$  vs. Temperature

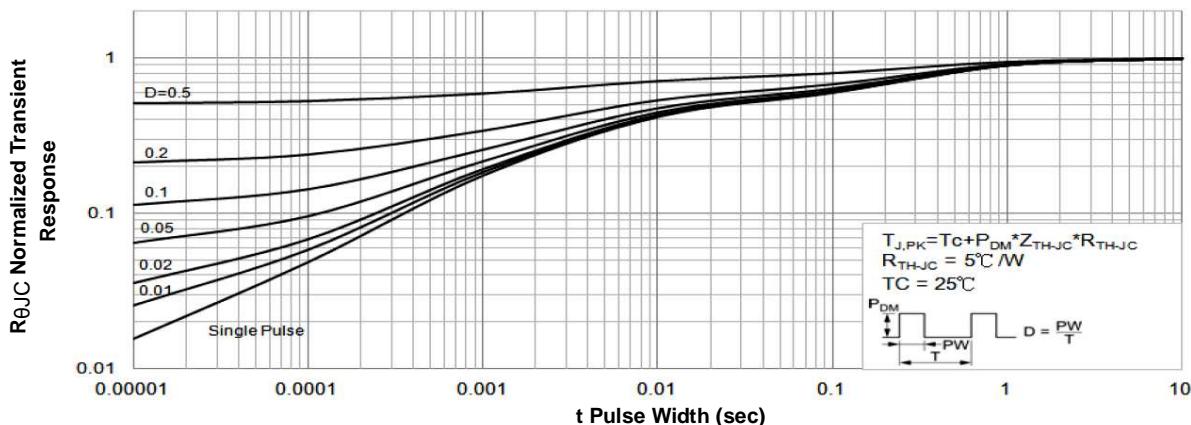


Fig.11 Normalized Maximum Transient Thermal Impedance